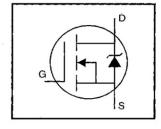
International Rectifier

IRF610PbF

HEXFET® Power MOSFET

- Dynamic dv/dt Rating
- Repetitive Avalanche Rated
- Fast Switching
- Ease of Paralleling
- Simple Drive Requirements
- Lead-Free

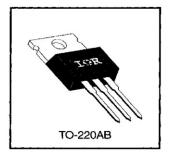


$$V_{DSS} = 200V$$
 $R_{DS(on)} = 1.5\Omega$
 $I_D = 3.3A$

Description

Third Generation HEXFETs from International Rectifier provide the designer with the best combination of fast switching, ruggedized device design, low on-resistance and cost-effectiveness.

The TO-220 package is universally preferred for all commercial-industrial applications at power dissipation levels to approximately 50 watts. The low thermal resistance and low package cost of the TO-220 contribute to its wide acceptance throughout the industry.



Absolute Maximum Ratings

	Parameter	Max.	Units			
I _D @ T _C = 25°C	Continuous Drain Current, VGS @ 10 V	3.3				
$I_D @ T_C = 100^{\circ}C$	Continuous Drain Current, VGS @ 10 V	2.1	Α			
I _{DM}	Pulsed Drain Current ①	10				
P _D @ T _C = 25°C	Power Dissipation	36	W			
	Linear Derating Factor	0.29	W/°C			
V _{GS} .	Gate-to-Source Voltage	±20	V			
Eas	Single Pulse Avalanche Energy ②	64	mJ			
IAR	Avalanche Current ①	3.3	A			
EAR	Repetitive Avalanche Energy ①	3.6	mJ			
dv/dt	Peak Diode Recovery dv/dt ③	5.0				
TJ	Operating Junction and	-55 to +150	.			
T _{STG}	Storage Temperature Range		°C			
	Soldering Temperature, for 10 seconds	300 (1.6mm from case)				
	Mounting Torque, 6-32 or M3 screw	10 lbf•in (1.1 N•m)				

Thermal Resistance

	Parameter	Min.	Тур.	Max.	Units
Reuc	Junction-to-Case	_	_	3.5	
Recs	Case-to-Sink, Flat, Greased Surface		0.50	_	°C/W
Reja	Junction-to-Ambient		-	62	

Electrical Characteristics @ T_J = 25°C (unless otherwise specified)

	Parameter	Min.	Тур.	Max.	Units	Test Conditions
V _{(BR)DSS}	Drain-to-Source Breakdown Voltage	200	_	_	V	V _{GS} =0V, I _D = 250μA
$\Delta V_{(BR)DSS}/\Delta T_{c}$	Breakdown Voltage Temp. Coefficient	_	0.30	-	V/°C	Reference to 25°C, I _D = 1mA
R _{DS(on)}	Static Drain-to-Source On-Resistance	_	_	1.5	Ω	V _{GS} =10V, I _D =2.0A ④
V _{GS(th)}	Gate Threshold Voltage	2.0	_	4.0	V	V _{DS} =V _{GS} , I _D = 250μA
gis	Forward Transconductance	0.80	-	_	S	V _{DS} =50V, I _D =2.0A ④
Ipss	Drain-to-Source Leakage Current	-	_	25	^	V _{DS} =200V, V _{GS} =0V
1088	Diam-to-Source Leakage Current		_	250	μΑ	V _{DS} =160V, V _{GS} =0V, T _J =125°C
Igss	Gate-to-Source Forward Leakage	_	-	100	nA	V _{GS} =20V
igss	Gate-to-Source Reverse Leakage	_	_	-100	IIA.	V _{GS} =-20V
Qg	Total Gate Charge	_		8.2		I _D =3.3A
Q_{gs}	Gate-to-Source Charge	_	_	1.8	nC	V _{DS} =160V
Q_{gd}	Gate-to-Drain ("Miller") Charge	_	_	4.5		V _{GS} =10V See Fig. 6 and 13 @
t _{d(on)}	Turn-On Delay Time		8.2		-	V _{DD} =100V
t _r	Rise Time		17	_	ns	I _D =3.3A
t _{d(off)}	Turn-Off Delay Time		14	_	113	$R_G=24\Omega$
t _f	Fall Time		8.9			R _D =30Ω See Figure 10 @
L _D	Internal Drain Inductance	_	4.5		nН	Between lead, 6 mm (0.25in.)
Ls	Internal Source Inductance	_	7.5	_	Ш	from package and center of die contact
Ciss	Input Capacitance	_	140	_		V _{GS} =0V
Coss	Output Capacitance	_	53		рF	V _{DS} =25V
Crss	Reverse Transfer Capacitance		15	_		f=1.0MHz See Figure 5

Source-Drain Ratings and Characteristics

	Parameter	Min.	Typ.	Max.	Units	Test Conditions
Is	Continuous Source Current (Body Diode)	-	_	3.3	^	MOSFET symbol showing the
I _{SM}	Pulsed Source Current (Body Diode) ①	-	_	10	Α	integral reverse p-n junction diode.
V _{SD}	Diode Forward Voltage	_	_	2.0	٧	T _J =25°C, I _S =3.3A, V _{GS} =0V @
t _{rr}	Reverse Recovery Time		150	310	ns	T _J =25°C, I _F =3.3A
Qrr	Reverse Recovery Charge	_	0.60	1.4	μС	di/dt=100A/μs ④
ton	Forward Turn-On Time	Intrinsi	Intrinsic turn-on time is neglegible (turn-on is dominated by Ls+LD)			

Notes:

- ① Repetitive rating; pulse width limited by max. junction temperature (See Figure 11)
- ③ IsD≤3.3A, di/dt≤70A/ μ s, V_{DD}≤V(BR)Dss, TJ≤150°C
- ④ Pulse width ≤ 300 μs; duty cycle ≤2%.

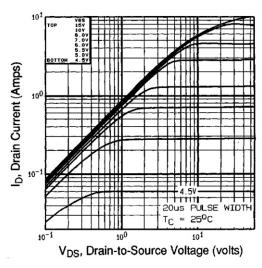


Fig 1. Typical Output Characteristics, $T_C=25^{\circ}C$

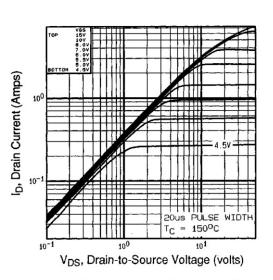


Fig 2. Typical Output Characteristics, T_C=150°C

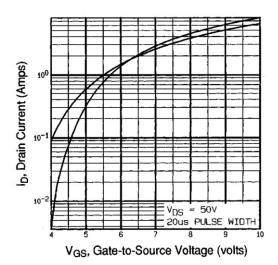


Fig 3. Typical Transfer Characteristics

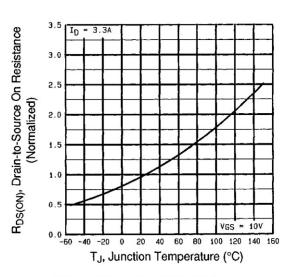


Fig 4. Normalized On-Resisance Vs. Temperature

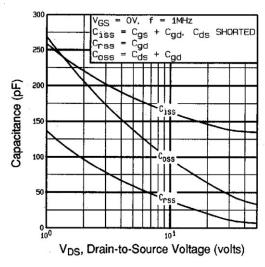


Fig 5. Typical Capacitance Vs. Drain-to-Source Voltage

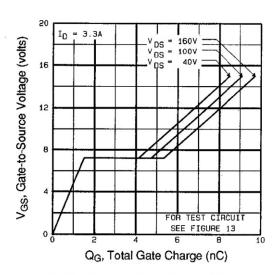


Fig 6. Typical Gate Charge Vs. Gate-to-Source Voltage

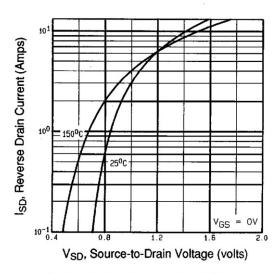


Fig 7. Typical Source-Drain Diode Forward Voltage

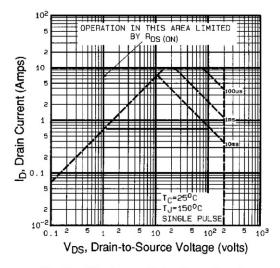


Fig 8. Maximum Safe Operating Area

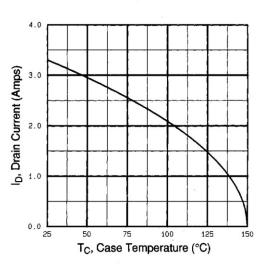


Fig 9. Maximum Drain Current Vs. Case Temperature

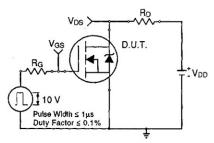


Fig 10a. Switching Time Test Circuit

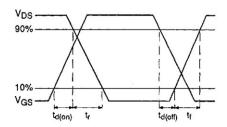


Fig 10b. Switching Time Waveforms

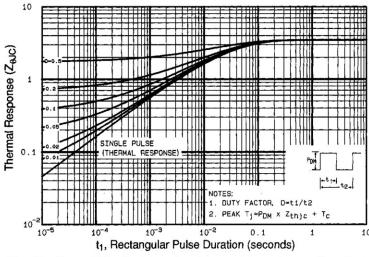


Fig 11. Maximum Effective Transient Thermal Impedance, Junction-to-Case

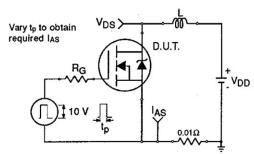


Fig 12a. Unclamped Inductive Test Circuit

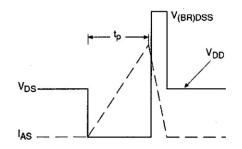


Fig 12b. Unclamped Inductive Waveforms

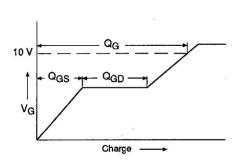


Fig 13a. Basic Gate Charge Waveform

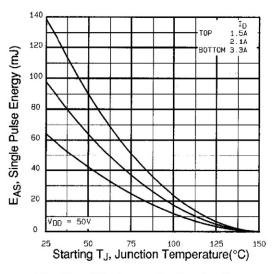


Fig 12c. Maximum Avalanche Energy Vs. Drain Current

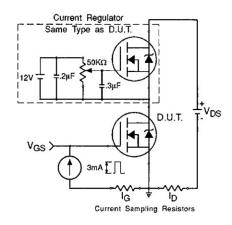


Fig 13b. Gate Charge Test Circuit

Appendix A: Figure 14, Peak Diode Recovery dv/dt Test Circuit - See page 1505

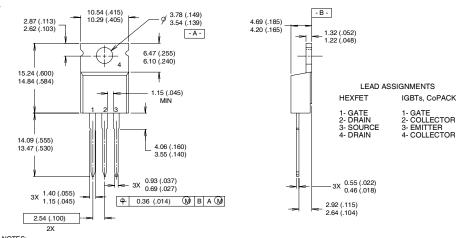
Appendix B: Package Outline Mechanical Drawing - See page 1509

Appendix E: Optional Leadforms - See page 1525



TO-220AB Package Outline

Dimensions are shown in millimeters (inches)



- NOTES:
- 1 DIMENSIONING & TOLERANCING PER ANSI Y14.5M, 1982.
- 3 OUTLINE CONFORMS TO JEDEC OUTLINE TO-220AB.
- 4 HEATSINK & LEAD MEASUREMENTS DO NOT INCLUDE BURRS.

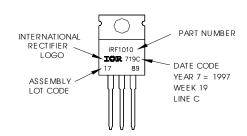
TO-220AB Part Marking Information

EXAMPLE: THIS IS AN IRF1010

LOT CODE 1789

ASSEMBLED ON WW 19, 1997 IN THE ASSEMBLY LINE "C"

Note: "P" in assembly line position indicates "Lead-Free"



Data and specifications subject to change without notice.



IR WORLD HEADQUARTERS: 233 Kansas St., El Segundo, California 90245, USA Tel: (310) 252-7105 TAC Fax: (310) 252-7903

02/04

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